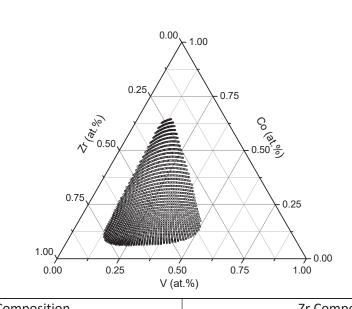
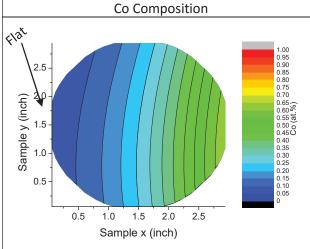
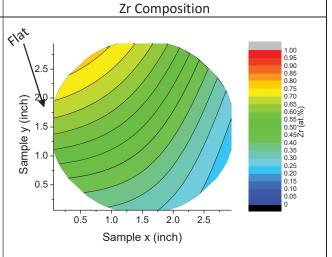


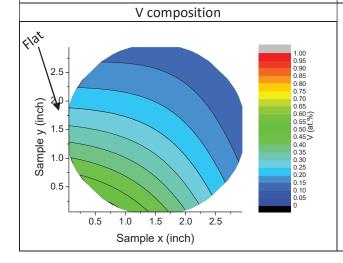


Sample Number	8 (scribed on back)
ID Code	MG-3/18/16-TMW-04
System	Co-Zr-V High Power Bottom







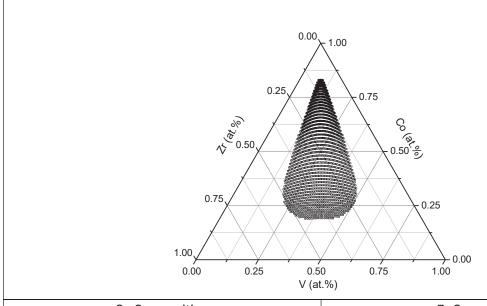


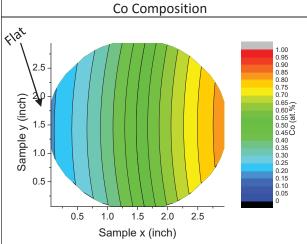
For all composition diagrams, the flat of the sample wafer is the left side of the diagram (the side which runs along the y-axis).

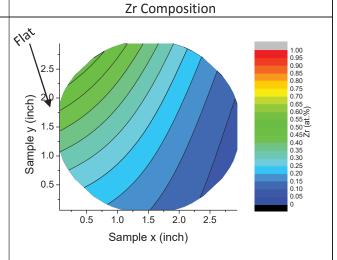
Composition diagrams were generated using an inhouse sputtering model.

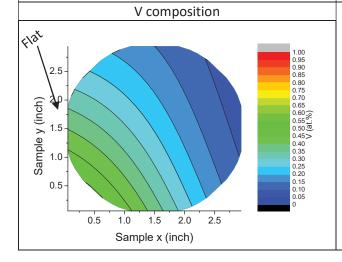
Sample Numbers are scribbed on the back of each sample

Sample Number	9 (scribed on back)
ID Code	MG-3/21/16-TMW-02
System	Co-Zr-V Low Power Top







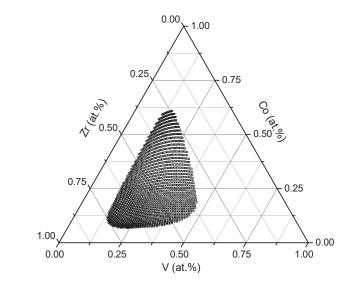


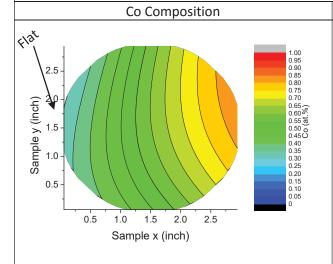
For all composition diagrams, the flat of the sample wafer is the left side of the diagram (the side which runs along the y-axis).

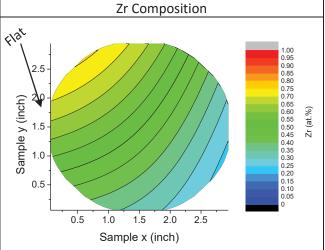
Composition diagrams were generated using an inhouse sputtering model.

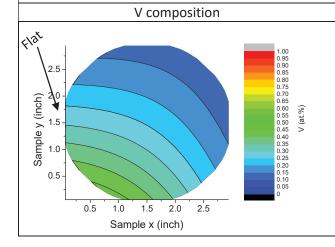
Sample Numbers are scribbed on the back of each sample

Sample Number	10 (scribed on back)
ID Code	MG-3/22/16-TMW-02
System	Co-Zr-V Low Power Bottom
System	Co-2r-V Low Power Bottom
	0.00









For all composition diagrams, the flat of the sample wafer is the left side of the diagram (the side which runs along the y-axis).

Composition diagrams were generated using an inhouse sputtering model.

Sample Numbers are scribbed on the back of each sample

